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## FEATURES

Hermetic package offers excellent long-term stability  
 0 g offset vs. temperature (all axes): 0.15 mg/°C maximum  
 Ultralow noise density (all axes): 20  $\mu\text{g}/\sqrt{\text{Hz}}$  (ADXL354)

Low power,  $V_{\text{SUPPLY}}$  (LDO enabled)

ADXL354 in measurement mode: 150  $\mu\text{A}$

ADXL355 in measurement mode: 200  $\mu\text{A}$

ADXL354/ADXL355 in standby mode: 21  $\mu\text{A}$

ADXL354 has user adjustable analog output bandwidth

ADXL355 digital output features

Digital serial peripheral interface (SPI)/I<sup>2</sup>C interfaces

20-bit analog-to-digital converter (ADC)

Data interpolation routine for synchronous sampling

Programmable high- and low-pass digital filters

Electromechanical self test

Integrated temperature sensor

Voltage range options

$V_{\text{SUPPLY}}$  with internal regulators: 2.25 V to 3.6 V

$V_{1\text{PBANA}}$ ,  $V_{1\text{PB8DIG}}$  with internal low dropout regulator (LDO)  
 bypassed: 1.8 V typical  $\pm$  10%

Operating temperature range: -40°C to +125°C

14-terminal, 6 mm  $\times$  6 mm  $\times$  2.1 mm, LCC package,  
 0.26 grams

## APPLICATIONS

Inertial measurement units (IMUs)/altitude and heading  
 reference systems (AHRSs)

Platform stabilization systems

Structural health monitoring

Seismic imaging

Tilt sensing

Robotics

Condition monitoring

## GENERAL DESCRIPTION

The analog output ADXL354 and the digital output ADXL355 are low noise density, low 0 g offset drift, low power, 3-axis accelerometers with selectable measurement ranges. The ADXL354B supports the  $\pm 2$  g and  $\pm 4$  g ranges, the ADXL354C supports the  $\pm 2$  g and  $\pm 8$  g ranges, and the ADXL355 supports the  $\pm 2.048$  g,  $\pm 4.096$  g, and  $\pm 8.192$  g ranges. The ADXL354/ADXL355 offer industry leading noise, minimal offset drift over temperature, and long term stability enabling precision applications with minimal calibration.

<sup>1</sup> Protected by U.S. Patents 8,472,270; 9,041,462; 8,665,627; 8,917,099; 6,892,576; 9,297,825; and 7,956,621.

Rev. 0

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## FUNCTIONAL BLOCK DIAGRAMS

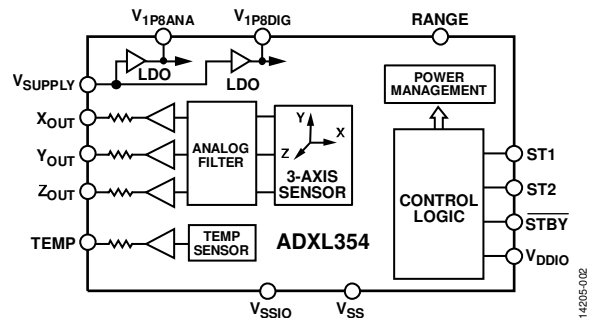


Figure 1. ADXL354 Functional Block Diagram

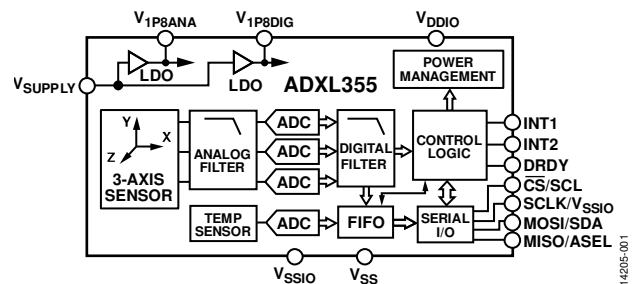


Figure 2. ADXL355 Functional Block Diagram

Highly integrated in a compact form factor, the low power ADXL355 is ideal in an Internet of Things (IoT) sensor node and other wireless product designs.

The ADXL355 multifunction pin names may be referenced by their relevant function only for either the SPI or I<sup>2</sup>C interfaces.

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**REVISION HISTORY**

9/2016—Revision 0: Initial Version

## SPECIFICATIONS

## ANALOG OUTPUT FOR THE ADXL354

$T_A = 25^\circ\text{C}$ ,  $V_{\text{SUPPLY}} = 3.3\text{ V}$ , x-axis acceleration and y-axis acceleration = 0 g, and z-axis acceleration = 1 g, unless otherwise noted.

Table 1.

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
SENSOR INPUT	Each axis				
Output Full-Scale Range (FSR)	ADXL354B, supports two ranges ADXL354C, supports two ranges		$\pm 2/\pm 4$ $\pm 2/\pm 8$		g
Resonant Frequency <sup>1</sup>			2.4		kHz
Nonlinearity	$\pm 2\text{ g}$		0.1		%
Cross Axis Sensitivity			1		%
SENSITIVITY	Ratiometric to $V_{1\text{PBANA}}$				
Sensitivity at $X_{\text{OUT}}$ , $Y_{\text{OUT}}$ , $Z_{\text{OUT}}$	$\pm 2\text{ g}$ $\pm 4\text{ g}$ $\pm 8\text{ g}$	368 184 92	400 200 100	432 216 108	mV/g mV/g mV/g
Sensitivity Change due to Temperature	$-40^\circ\text{C}$ to $+125^\circ\text{C}$		$\pm 0.01$		%/ $^\circ\text{C}$
0 g OFFSET	Each axis, $\pm 2\text{ g}$				
0 g Output for $X_{\text{OUT}}$ , $Y_{\text{OUT}}$ , $Z_{\text{OUT}}$	Referred to $V_{1\text{PBANA}}/2$	-75	$\pm 25$	+75	mg
0 g Offset vs. Temperature (X-Axis, Y-Axis, and Z-Axis) <sup>2</sup>	$-40^\circ\text{C}$ to $+125^\circ\text{C}$	-0.15	$\pm 0.1$	+0.15	mg/ $^\circ\text{C}$
Repeatability <sup>3</sup>	X-axis and y-axis Z-axis		$\pm 3.5$ $\pm 9$		mg mg
Vibration Rectification Error (VRE) <sup>4</sup>	$\pm 2\text{ g}$ range, in a 1 g orientation, offset due to 2.5 g rms vibration		<0.4		g
NOISE DENSITY	$\pm 2\text{ g}$				
X-Axis, Y-Axis, and Z-Axis			20		$\mu\text{g}/\sqrt{\text{Hz}}$
Velocity Random Walk	X-axis and y-axis Z-axis		9 13		$\mu\text{m}/\text{sec}/\sqrt{\text{Hr}}$ $\mu\text{m}/\text{sec}/\sqrt{\text{Hr}}$
BANDWIDTH					
Internal Low-Pass Filter Frequency	Fixed frequency, 50% response attenuation		1500		Hz
SELF TEST					
Output Change					
X-Axis			0.3		g
Y-Axis			0.3		g
Z-Axis			1.5		g
POWER SUPPLY					
Voltage Range					
$V_{\text{SUPPLY}}^5$		2.25	2.5	3.6	V
$V_{\text{DDIO}}$		$V_{1\text{PB8DIG}}$	2.5	3.6	V
$V_{1\text{PBANA}}$ , $V_{1\text{PB8DIG}}$ with Internal Low Dropout Regulator (LDO) Bypassed	$V_{\text{SUPPLY}} = 0\text{ V}$	1.62	1.8	1.98	V
Current					
Measurement Mode					
$V_{\text{SUPPLY}}$ (LDO Enabled)			150		$\mu\text{A}$
$V_{1\text{PBANA}}$ (LDO Disabled)			138		$\mu\text{A}$
$V_{1\text{PB8DIG}}$ (LDO Disabled)			12		$\mu\text{A}$
Standby Mode					
$V_{\text{SUPPLY}}$ (LDO Enabled)			21		$\mu\text{A}$
$V_{1\text{PBANA}}$ (LDO Disabled)			7		$\mu\text{A}$
$V_{1\text{PB8DIG}}$ (LDO Disabled)			10		$\mu\text{A}$
Turn On Time <sup>6</sup>	2 g range Power-off to standby		<10 <10		ms ms

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
OUTPUT AMPLIFIER					
Swing	No load	0.03		$V_{IP8ANA} - 0.03$	V
Output Series Resistance			32		k $\Omega$
TEMPERATURE SENSOR					
Output at 25°C			892.2		mV
Scale Factor			3.0		mV/°C
TEMPERATURE					
Operating Temperature Range		-40		+125	°C

<sup>1</sup> The resonant frequency is a sensor characteristic. An integrated analog 1.5 kHz (-6 dB) sinc low-pass filter that cannot be bypassed limits the actual output response.

<sup>2</sup> The temperature change is -40°C to +25°C or +25°C to +125°C.

<sup>3</sup> Repeatability is predicted for a 10 year life and includes shifts due to the high temperature operating life test (HTOL) ( $T_A = 150^\circ\text{C}$ ,  $V_{SUPPLY} = 3.6\text{ V}$ , and 1000 hours), temperature cycling (-55°C to +125°C and 1000 cycles), velocity random walk, broadband noise, and temperature hysteresis.

<sup>4</sup> The VRE measurement is the shift in dc offset while the device is subject to 2.5 g rms of random vibration from 50 Hz to 2 kHz. The device under test (DUT) is configured for the  $\pm 2\text{ g}$  range and an output data rate of 4 kHz. The VRE scales with the range setting.

<sup>5</sup> When  $V_{IP8ANA}$  and  $V_{IP8DIG}$  are generated internally,  $V_{SUPPLY}$  is valid. To disable the LDO and drive  $V_{IP8ANA}$  and  $V_{IP8DIG}$  externally, connect  $V_{SUPPLY}$  to  $V_{SS}$ .

<sup>6</sup> Standby to measurement mode; valid when the output is within 1 mg of the final value.

## DIGITAL OUTPUT FOR THE ADXL355

$T_A = 25^\circ\text{C}$ ,  $V_{SUPPLY} = 3.3\text{ V}$ , x-axis acceleration and y-axis acceleration = 0 g, and z-axis acceleration = 1 g, and output data rate (ODR) = 500 Hz, unless otherwise noted. Note that multifunction pin names may be referenced by their relevant function only.

Table 2.

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
SENSOR INPUT					
Output Full Scale Range (FSR)	Each axis User selectable		$\pm 2.048$ $\pm 4.096$ $\pm 8.192$		g g g
Nonlinearity	$\pm 2\text{ g}$		0.1		% FS
Cross Axis Sensitivity			1		%
SENSITIVITY					
X-Axis, Y-Axis, and Z-Axis Sensitivity	Each axis $\pm 2\text{ g}$ $\pm 4\text{ g}$ $\pm 8\text{ g}$	235,520 117,760 58,880	256,000 128,000 64,000	276,480 138,240 69,120	LSB/g LSB/g LSB/g
X-Axis, Y-Axis, and Z-Axis Scale Factor	$\pm 2\text{ g}$ $\pm 4\text{ g}$ $\pm 8\text{ g}$		3.9 7.8 15.6		$\mu\text{g}/\text{LSB}$ $\mu\text{g}/\text{LSB}$ $\mu\text{g}/\text{LSB}$
Sensitivity Change due to Temperature	-40°C to +125°C		$\pm 0.01$		%/°C
0 g OFFSET					
X-Axis, Y-Axis, and Z-Axis 0 g Output	Each axis, $\pm 2\text{ g}$	-75	$\pm 25$	+75	mg
0 g Offset vs. Temperature (X-Axis, Y-Axis, and Z-Axis) <sup>1</sup>	-40°C to +125°C	-0.15	$\pm 0.02$	+0.15	mg/°C
Repeatability <sup>2</sup>	X-axis and y-axis Z-axis		$\pm 3.5$ $\pm 9$		mg mg
Vibration Rectification <sup>3</sup>	$\pm 2\text{ g}$ range, in a 1 g orientation, offset due to 2.5 g rms vibration		<0.4		g
NOISE DENSITY					
X-Axis, Y-Axis, and Z-Axis Velocity Random Walk	$\pm 2\text{ g}$ X-axis and y-axis Z-axis		25 9 13		$\mu\text{g}/\sqrt{\text{Hz}}$ $\mu\text{m}/\text{sec}/\sqrt{\text{Hr}}$ $\mu\text{m}/\text{sec}/\sqrt{\text{Hr}}$
OUTPUT DATA RATE AND BANDWIDTH					
Low-Pass Filter Passband Frequency	User programmable, Register 0x28	1		1000	Hz
High-Pass Filter Passband Frequency When Enabled (Disabled by Default)	User programmable, Register 0x28 for 4 kHz ODR	0.0095		10	Hz

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
SELF TEST					
Output Change					
X-Axis			0.3		g
Y-Axis			0.3		g
Z-Axis			1.5		g
POWER SUPPLY					
Voltage Range					
$V_{SUPPLY}$ Operating <sup>4</sup>		2.25	2.5	3.6	V
$V_{DDIO}$		$V_{1PB8DIG}$	2.5	3.6	V
$V_{1PB8ANA}$ and $V_{1PB8DIG}$ with Internal LDO Bypassed	$V_{SUPPLY} = 0\text{ V}$	1.62	1.8	1.98	V
Current					
Measurement Mode					
$V_{SUPPLY}$ (LDO Enabled)			200		$\mu\text{A}$
$V_{1PB8ANA}$ (LDO Disabled)			160		$\mu\text{A}$
$V_{1PB8DIG}$ (LDO Disabled)			35.5		$\mu\text{A}$
Standby Mode					
$V_{SUPPLY}$ (LDO Enabled)			21		$\mu\text{A}$
$V_{1PB8ANA}$ (LDO Disabled)			7		$\mu\text{A}$
$V_{1PB8DIG}$ (LDO Disabled)			10		$\mu\text{A}$
Turn On Time <sup>5</sup>	2 g range Power-off to standby		<10 <10		ms ms
TEMPERATURE SENSOR					
Output at 25°C			1852		LSB
Scale Factor			-9.05		LSB/°C
TEMPERATURE					
Operating Temperature Range		-40		+125	°C

<sup>1</sup> The temperature change is -40°C to +25°C or +25°C to +125°C.

<sup>2</sup> Repeatability is predicted for a 10 year life and includes shifts due to the HTOL ( $T_A = 150^\circ\text{C}$ ,  $V_{SUPPLY} = 3.6\text{ V}$ , and 1000 hours), temperature cycling (-55°C to +125°C and 1000 cycles), velocity random walk, broadband noise, and temperature hysteresis.

<sup>3</sup> The VRE measurement is the shift in dc offset while the device is subject to 2.5 g rms random vibration from 50 Hz to 2 kHz. The DUT is configured for the  $\pm 2\text{ g}$  range and an output data rate of 4 kHz. The VRE scales with the range setting.

<sup>4</sup> When  $V_{1PB8ANA}$  and  $V_{1PB8DIG}$  are generated internally,  $V_{SUPPLY}$  is valid. To disable the LDO and drive  $V_{1PB8ANA}$  and  $V_{1PB8DIG}$  externally, connect  $V_{SUPPLY}$  to  $V_{SS}$ .

<sup>5</sup> Standby to measurement mode; valid when the output is within 1 mg of final value.

## SPI DIGITAL INTERFACE CHARACTERISTICS FOR THE ADXL355

Note that multifunction pin names may be referenced by their relevant function only.

Table 3.

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
DC INPUT LEVELS						
Input Voltage						
Low Level	$V_{IL}$				$0.3 \times V_{DDIO}$	V
High Level	$V_{IH}$		$0.7 \times V_{DDIO}$			V
Input Current						
Low Level	$I_{IL}$	$V_{IN} = 0\text{ V}$	-0.1			$\mu\text{A}$
High Level	$I_{IH}$	$V_{IN} = V_{DDIO}$			0.1	$\mu\text{A}$
DC OUTPUT LEVELS						
Output Voltage						
Low Level	$V_{OL}$	$I_{OL} = I_{OL, MIN}$			$0.2 \times V_{DDIO}$	V
High Level	$V_{OH}$	$I_{OH} = I_{OH, MAX}$	$0.8 \times V_{DDIO}$			V
Output Current						
Low Level	$I_{OL}$	$V_{OL} = V_{OL, MAX}$	-10			mA
High Level	$I_{OH}$	$V_{OH} = V_{OH, MIN}$			4	mA

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
AC INPUT LEVELS						
SCLK Frequency			0.1		10	MHz
SCLK High Time	$t_{HIGH}$		40			ns
SCLK Low Time	$t_{LOW}$		40			ns
$\overline{CS}$ Setup Time	$t_{CSS}$		20			ns
$\overline{CS}$ Hold Time	$t_{CSH}$		20			ns
$\overline{CS}$ Disable Time	$t_{CSD}$		40			ns
Rising SCLK Setup Time	$t_{SCLKS}$		20			ns
MOSI Setup Time	$t_{SU}$		20			ns
MOSI Hold Time	$t_{HD}$		20			ns
AC OUTPUT LEVELS						
Propagation Delay	$t_P$	$C_{LOAD} = 30 \text{ pF}$			30	ns
Enable MISO Time	$t_{EN}$		30			ns
Disable MISO Time	$t_{DIS}$				20	ns

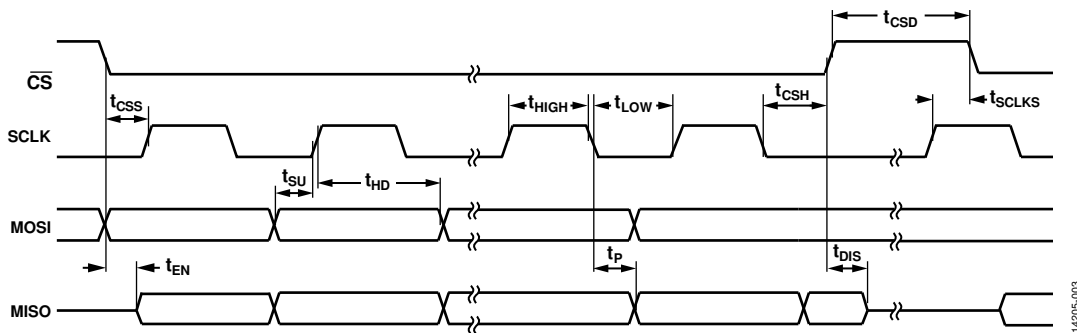


Figure 3. SPI Interface Timing Diagram

**I<sup>2</sup>C DIGITAL INTERFACE CHARACTERISTICS FOR THE ADXL355**

Note that multifunction pin names may be referenced by their relevant function only.

Table 4.

Parameter	Symbol	Test Conditions/ Comments	I2C_HS = 0 (Fast Mode)			I2C_HS = 1 (High Speed Mode)			Unit
			Min	Typ	Max	Min	Typ	Max	
DC INPUT LEVELS									
Input Voltage									
Low Level	$V_{IL}$				$0.3 \times V_{DDIO}$			$0.3 \times V_{DDIO}$	V
High Level	$V_{IH}$		$0.7 \times V_{DDIO}$			$0.7 \times V_{DDIO}$			V
Hysteresis of Schmitt Trigger Inputs	$V_{HYS}$		$0.05 \times V_{DDIO}$			$0.1 \times V_{DDIO}$			$\mu A$
Input Current	$I_{IL}$	$0.1 \times V_{DDIO} < V_{IN} < 0.9 \times V_{DDIO}$	-10		+10				$\mu A$
DC OUTPUT LEVELS									
Output Voltage									
Low Level	$V_{OL1}$ $V_{OL2}$	$I_{OL} = 3 \text{ mA}$ $V_{DD} > 2 \text{ V}$ $V_{DD} \leq 2 \text{ V}$			0.4			$0.2 \times V_{DDIO}$	V V
Output Current									
Low Level	$I_{OL}$	$V_{OL} = 0.4 \text{ V}$ $V_{OL} = 0.6 \text{ V}$	20 6						$\text{mA}$ $\text{mA}$

Parameter	Symbol	Test Conditions/ Comments	I2C_HS = 0 (Fast Mode)			I2C_HS = 1 (High Speed Mode)			Unit
			Min	Typ	Max	Min	Typ	Max	
AC INPUT LEVELS									
SCLK Frequency			0		1	0		3.4	MHz
SCL High Time	t <sub>HIGH</sub>		260			60			ns
SCL Low Time	t <sub>LOW</sub>		500			160			ns
Start Setup Time	t <sub>SUSTA</sub>		260			160			ns
Start Hold Time	t <sub>HDSTA</sub>		260			160			ns
SDA Setup Time	t <sub>SUDAT</sub>		50			10			ns
SDA Hold Time	t <sub>HDDAT</sub>		0			0			ns
Stop Setup Time	t <sub>SUSTO</sub>		260			160			ns
Bus Free Time	t <sub>BUF</sub>		500						ns
SCL Input Rise Time	t <sub>RCL</sub>				120			80	ns
SCL Input Fall Time	t <sub>FCL</sub>				120			80	ns
SDA Input Rise Time	t <sub>RDA</sub>				120			160	ns
SDA Input Fall Time	t <sub>FDA</sub>				120			160	ns
Width of Spikes to Suppress	t <sub>SP</sub>	Not shown in Figure 4			50			10	ns
AC OUTPUT LEVELS									
Propagation Delay Data	t <sub>VDDAT</sub>	C <sub>LOAD</sub> = 500 pF	97		450	27		135	ns
Acknowledge	t <sub>VDACK</sub>				450				ns
Output Fall Time	t <sub>F</sub>	Not shown in Figure 4	20 × (V <sub>DD</sub> /5.5)		120				ns

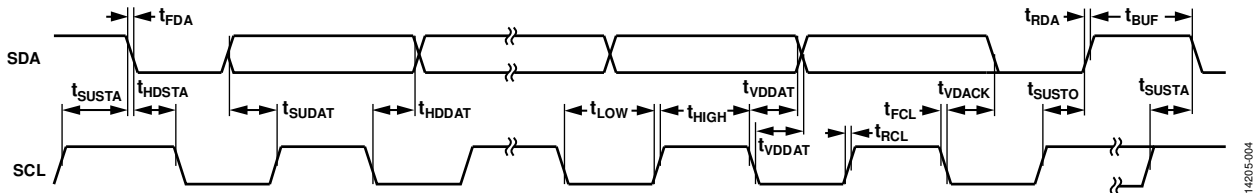


Figure 4. I<sup>2</sup>C Interface Timing Diagram

14205-004



## ABSOLUTE MAXIMUM RATINGS

Table 5.

Parameter	Rating
Acceleration (Any Axis, 0.1 ms) Unpowered	5,000 <i>g</i>
$V_{\text{SUPPLY}}, V_{\text{DDIO}}$	5.4 V
$V_{\text{IP8ANA}}, V_{\text{IP8DIG}}$ Configured as Inputs	1.98 V
<b>ADXL354</b>	
Digital Inputs (RANGE, ST1, ST2, $\overline{\text{STBY}}$ )	-0.3 V to $V_{\text{DDIO}} + 0.3$ V
Analog Outputs ( $X_{\text{OUT}}, Y_{\text{OUT}}, Z_{\text{OUT}}, \text{TEMP}$ )	-0.3 V to $V_{\text{IP8ANA}} + 0.3$ V
<b>ADXL355</b>	
Digital Pins ( $\overline{\text{CS}}, \text{SCLK}, \text{MOSI}, \text{MISO}, \text{INT1}, \text{INT2}, \text{DRDY}$ )	-0.3 V to $V_{\text{DDIO}} + 0.3$ V
Operating Temperature Range	-40°C to +125°C
Storage Temperature Range	-55°C to +150°C

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

## THERMAL RESISTANCE

Thermal performance is directly linked to printed circuit board (PCB) design and operating environment. Careful attention to PCB thermal design is required.

Table 6. Thermal Resistance

Package Type	$\theta_{\text{JA}}$	Unit
E-14-1 <sup>1</sup>	42	°C/W

<sup>1</sup> Thermal impedance simulated values are based on a JEDEC 252P thermal test board with four thermal vias. See JEDEC JESD51.

## ESD CAUTION



**ESD (electrostatic discharge) sensitive device.** Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

## PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

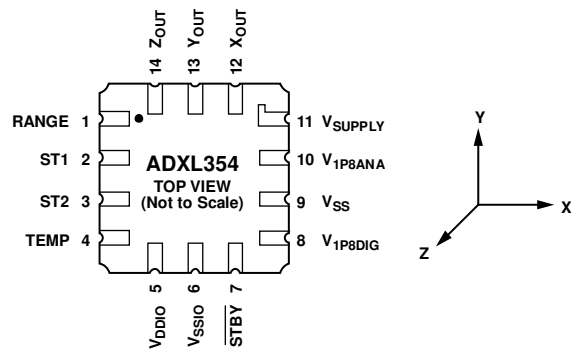


Figure 5. ADXL354 Pin Configuration

Table 7. ADXL354 Pin Function Descriptions

Pin No.	Mnemonic	Description
1	RANGE	Range Selection Pin. Set this pin to ground to select the $\pm 2 g$ range, or set this pin to $V_{DDIO}$ to select the $\pm 4 g$ or $\pm 8 g$ range. This pin is model dependent (see the Ordering Guide section).
2	ST1	Self Test Pin 1. This pin enables self test mode.
3	ST2	Self Test Pin 2. This pin activates the electromechanical self test actuation.
4	TEMP	Temperature Sensor Output.
5	$V_{DDIO}$	Digital Interface Supply Voltage.
6	$V_{SSIO}$	Digital Ground.
7	$\overline{STBY}$	Standby or Measurement Mode Selection Pin. Set this pin to ground to enter standby mode, or set this pin to $V_{DDIO}$ to enter measurement mode.
8	$V_{1P8DIG}$	Digital Supply. This pin requires a decoupling capacitor. If $V_{SUPPLY}$ connects to $V_{SS}$ , supply the voltage to this pin externally.
9	$V_{SS}$	Analog Ground.
10	$V_{1P8ANA}$	Analog Supply. This pin requires a decoupling capacitor. If $V_{SUPPLY}$ connects to $V_{SS}$ , supply the voltage to this pin externally.
11	$V_{SUPPLY}$	Supply Voltage. When $V_{SUPPLY}$ equals 2.25 V to 3.6 V, $V_{SUPPLY}$ enables the internal LDOs to generate $V_{1P8DIG}$ and $V_{1P8ANA}$ . For $V_{SUPPLY} = V_{SS}$ , $V_{1P8DIG}$ and $V_{1P8ANA}$ are externally supplied.
12	$X_{OUT}$	X-Axis Output.
13	$Y_{OUT}$	Y-Axis Output.
14	$Z_{OUT}$	Z-Axis Output.

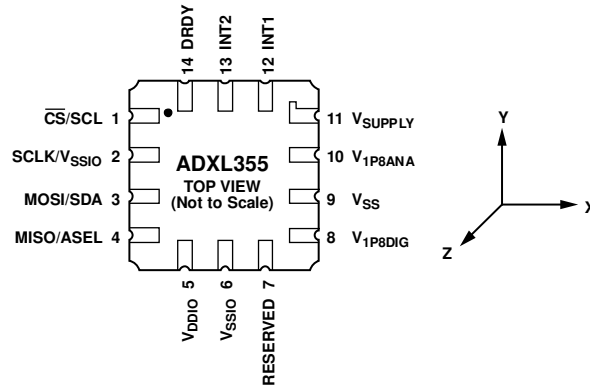


Figure 6. ADXL355 Pin Configuration

142205-006

Table 8. ADXL355 Pin Function Descriptions

Pin No.	Mnemonic	Description
1	CS/SCL	Chip Select for SPI (CS). Serial Communications Clock for I <sup>2</sup> C (SCL).
2	SCLK/VSSIO	Serial Communications Clock for SPI (SCLK). Connect to VSSIO for I <sup>2</sup> C (VSSIO).
3	MOSI/SDA	Master Output, Slave Input for SPI (MOSI). Serial Data for I <sup>2</sup> C (SDA).
4	MISO/ASEL	Master Input, Slave Output for SPI (MISO). Alternate I <sup>2</sup> C Address Select for I <sup>2</sup> C (ASEL).
5	VDDIO	Digital Interface Supply Voltage.
6	VSSIO	Digital Ground.
7	RESERVED	Reserved. This pin can be connected to ground or left open.
8	V1P8DIG	Digital Supply. This pin requires a decoupling capacitor. If VSUPPLY connects to VSS, supply the voltage to this pin externally.
9	VSS	Analog Ground.
10	V1P8ANA	Analog Supply. This pin requires a decoupling capacitor. If VSUPPLY connects to VSS, supply the voltage to this pin externally.
11	VSUPPLY	Supply Voltage. When VSUPPLY equals 2.25 V to 3.6 V, VSUPPLY enables the internal LDOs to generate V1P8DIG and V1P8ANA. For VSUPPLY = VSS, V1P8DIG and V1P8ANA are externally supplied.
12	INT1	Interrupt Pin 1.
13	INT2	Interrupt Pin 2.
14	DRDY	Data Ready Pin.

# TYPICAL PERFORMANCE CHARACTERISTICS

All figures include data for multiple devices and multiple lots, and they were taken in the  $\pm 2 g$  range, unless otherwise noted.

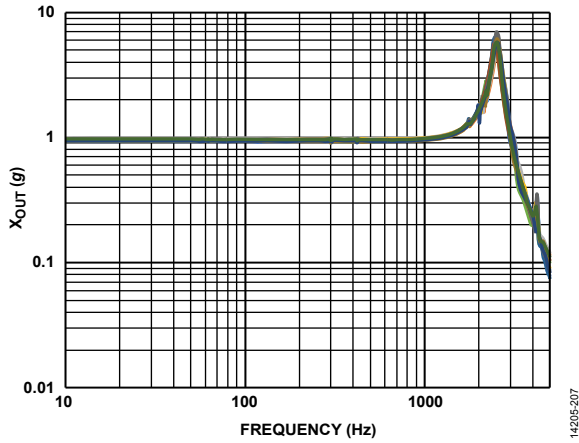


Figure 7. ADXL354 Frequency Response for X-Axis

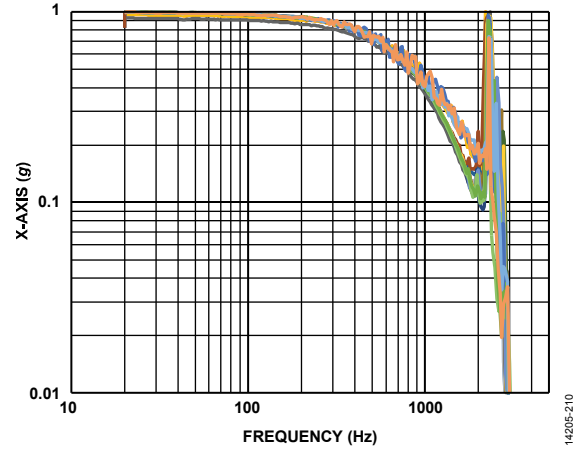


Figure 10. ADXL355 Normalized Frequency Response for X-Axis at 4 kHz ODR

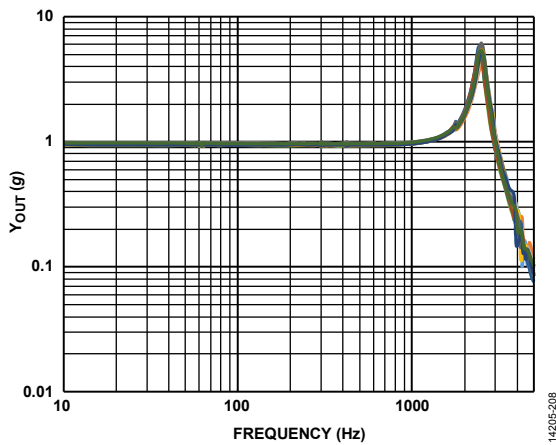


Figure 8. ADXL354 Frequency Response for Y-Axis

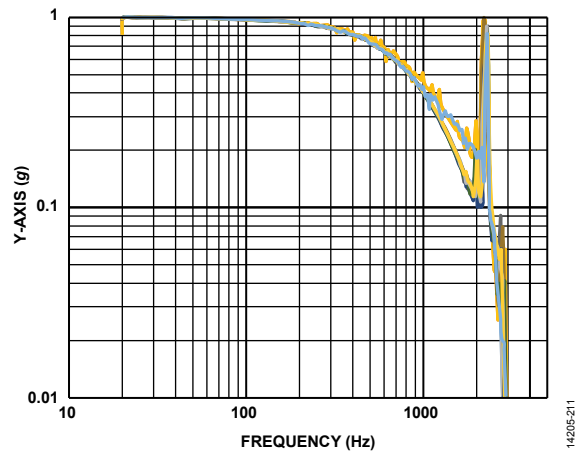


Figure 11. ADXL355 Normalized Frequency Response for Y-Axis at 4 kHz ODR

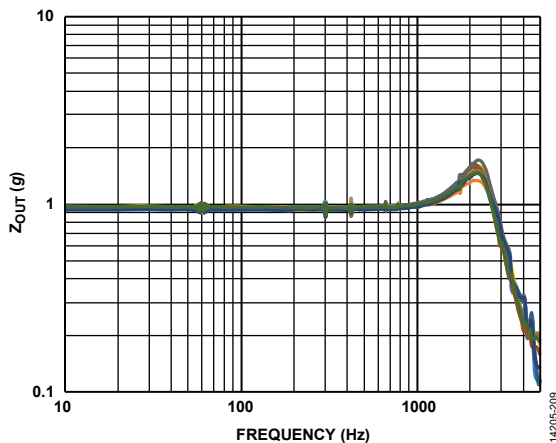


Figure 9. ADXL354 Frequency Response for Z-Axis

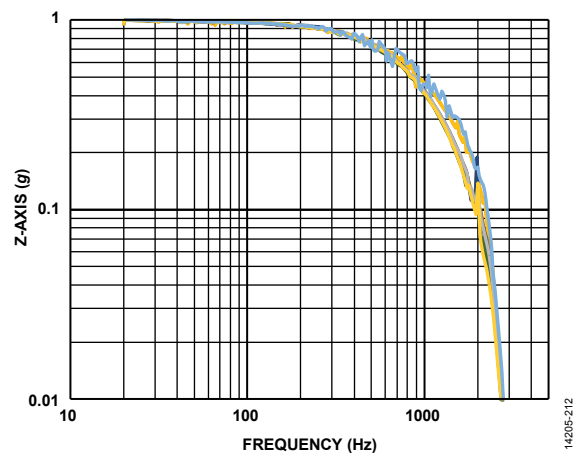


Figure 12. ADXL355 Normalized Frequency Response for Z-Axis at 4 kHz ODR

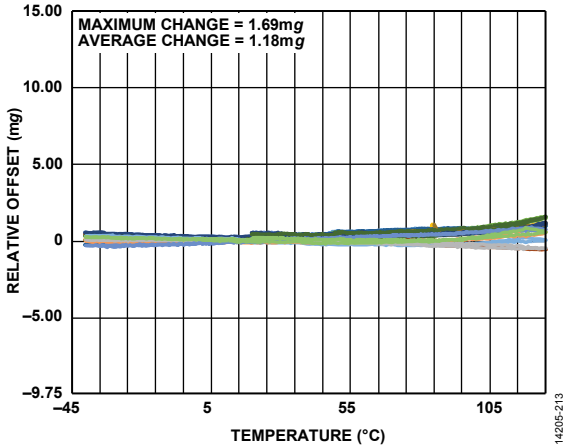


Figure 13. ADXL354 X-Axis Zero g Offset Relative to 25°C vs. Temperature

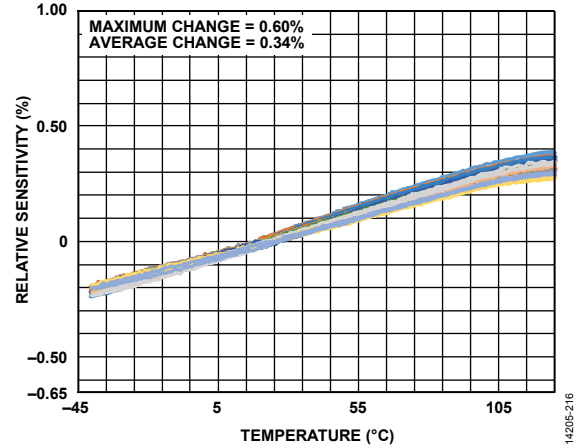


Figure 16. ADXL354 X-Axis Sensitivity Relative to 25°C vs. Temperature

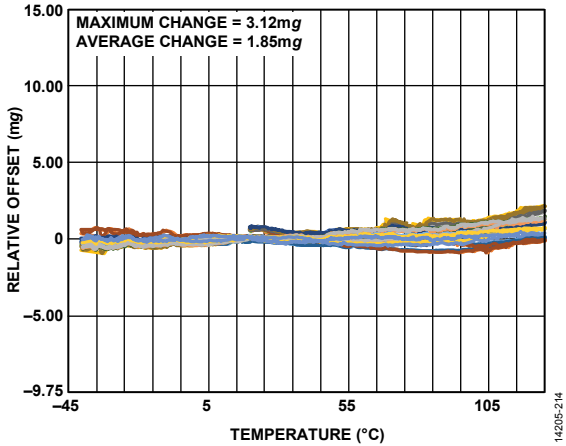


Figure 14. ADXL354 Y-Axis Zero g Offset Relative to 25°C vs. Temperature

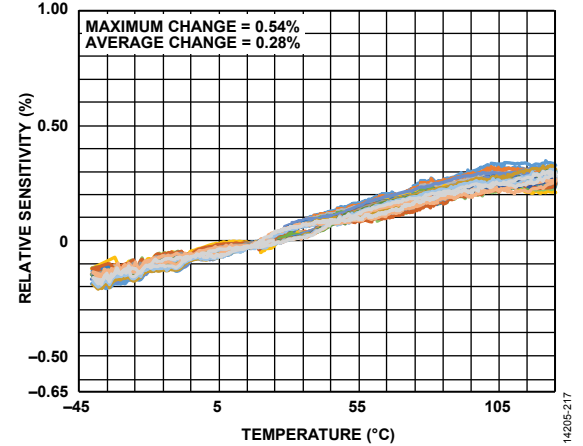


Figure 17. ADXL354 Y-Axis Sensitivity Relative to 25°C vs. Temperature

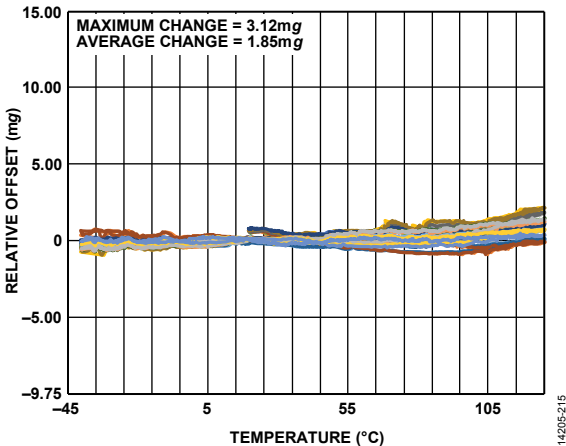


Figure 15. ADXL354 Z-Axis Zero g Offset Relative to 25°C vs. Temperature

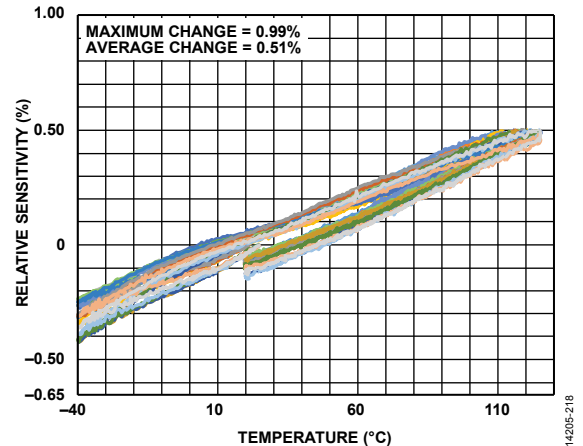
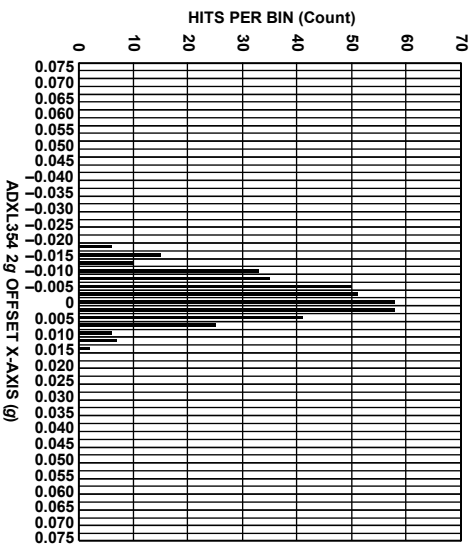
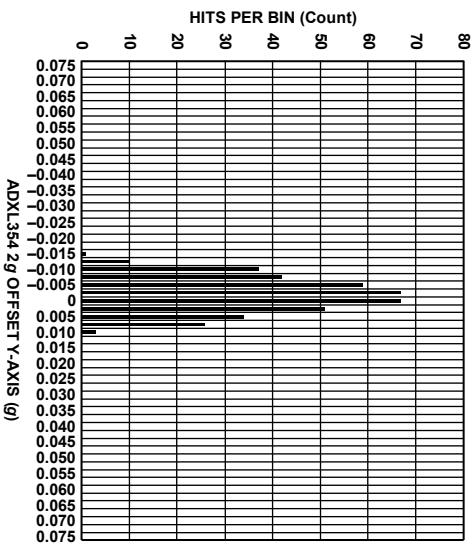


Figure 18. ADXL354 Z-Axis Sensitivity Relative to 25°C vs. Temperature



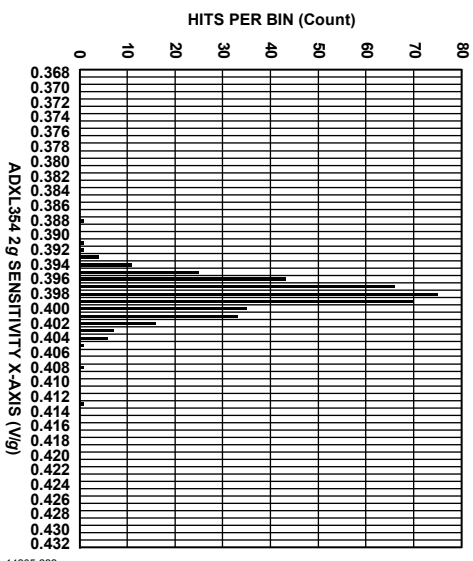
14205-219

Figure 19. ADXL354 Zero g Offset Histogram at 25°C, X-Axis



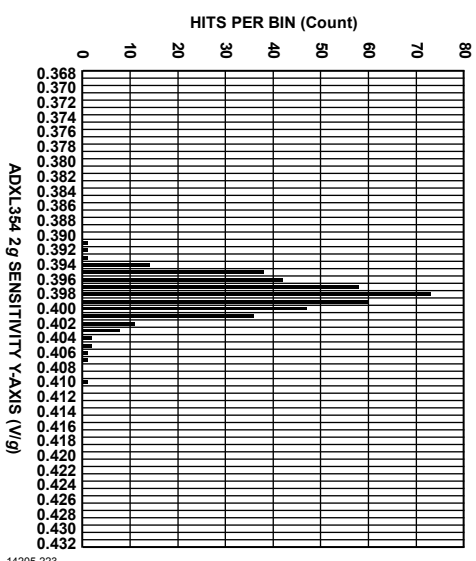
14205-220

Figure 20. ADXL354 Zero g Offset Histogram at 25°C, Y-Axis



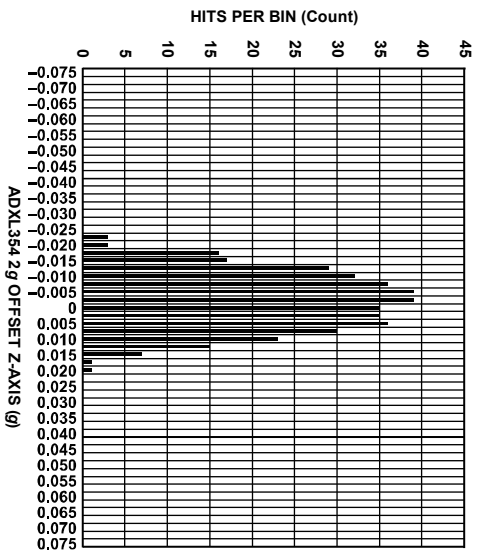
14205-222

Figure 22. ADXL354 Sensitivity Histogram at 25°C, X-Axis



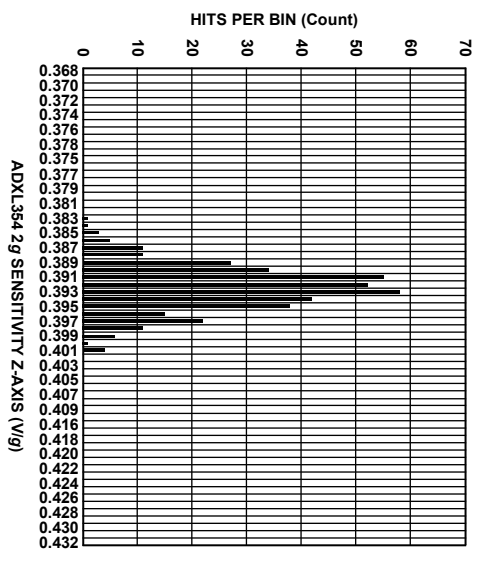
14205-223

Figure 23. ADXL354 Sensitivity Histogram at 25°C, Y-Axis



14205-221

Figure 21. ADXL354 Zero g Offset Histogram at 25°C, Z-Axis



14205-224

Figure 24. ADXL354 Sensitivity Histogram at 25°C, Z-Axis

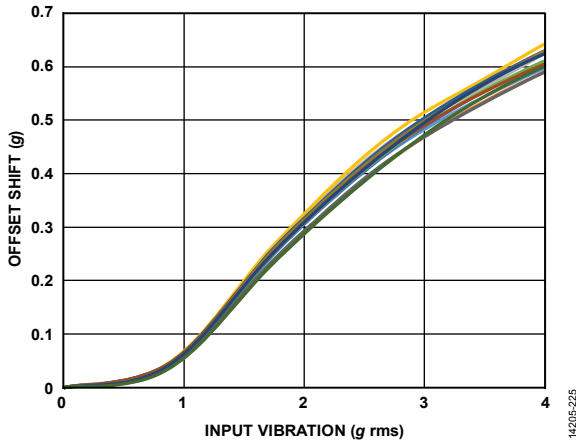


Figure 25. ADXL354 Vibration Rectification Error (VRE), X-Axis Offset from +1 g, ±2 g Range, X-Axis Orientation = -1 g

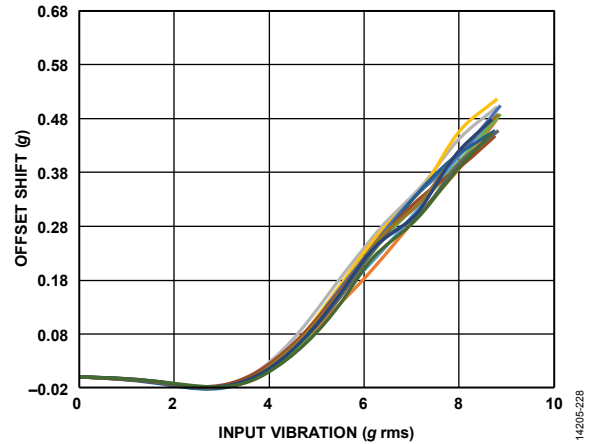


Figure 28. ADXL354 Vibration Rectification Error (VRE), X-Axis Offset from +1 g, ±8 g Range, X-Axis Orientation = -1 g

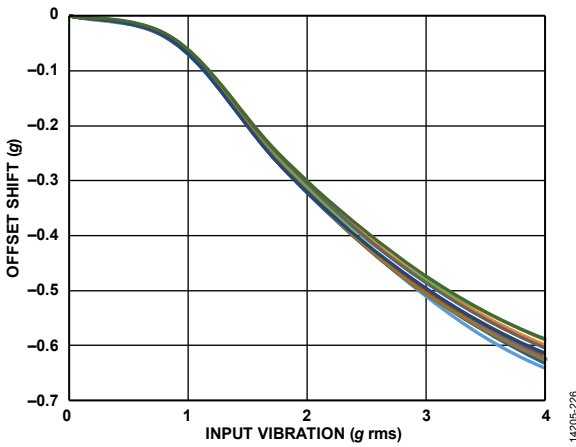


Figure 26. ADXL354 Vibration Rectification Error (VRE), Y-Axis Offset from +1 g, ±2 g Range, Y-Axis Orientation = +1 g

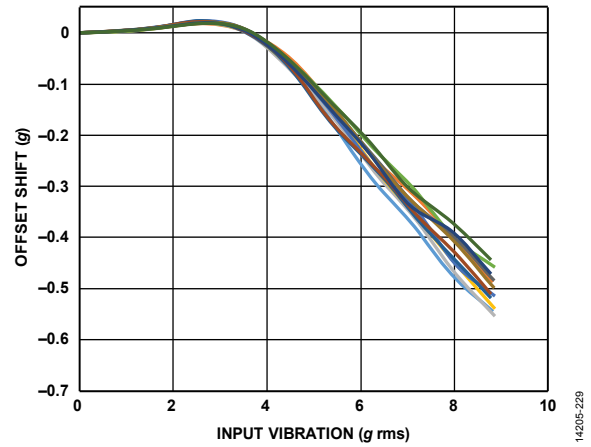


Figure 29. ADXL354 Vibration Rectification Error (VRE), Y-Axis Offset from +1 g, ±8 g Range, Y-Axis Orientation = +1 g

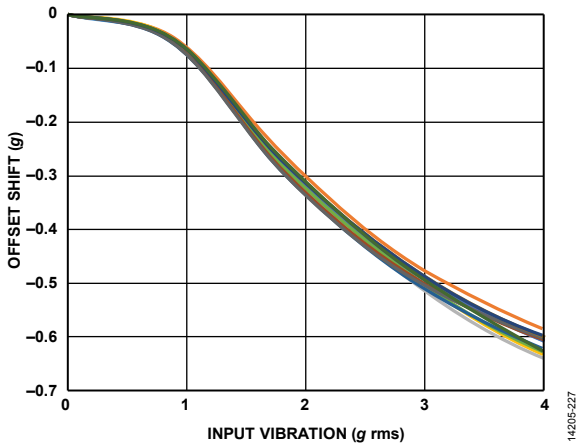


Figure 27. ADXL354 Vibration Rectification Error (VRE), Z-Axis Offset from +1 g, ±2 g Range, Z-Axis Orientation = +1 g

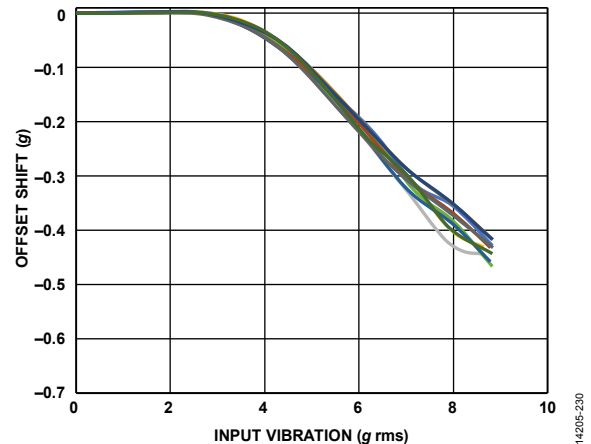


Figure 30. ADXL354 Vibration Rectification Error (VRE), Z-Axis Offset from +1 g, ±8 g Range, Z-Axis Orientation = +1 g

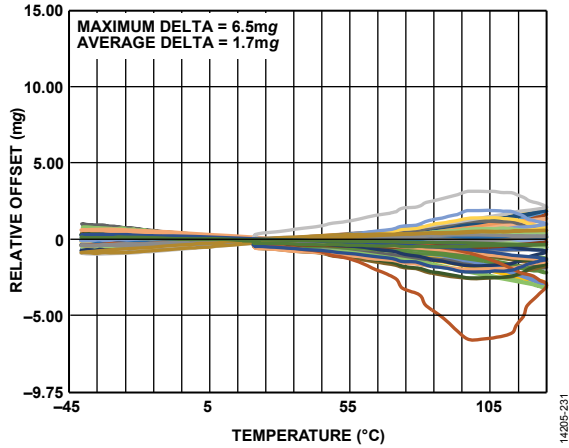


Figure 31. ADXL355 X-Axis Zero g Offset Relative to 25°C vs. Temperature

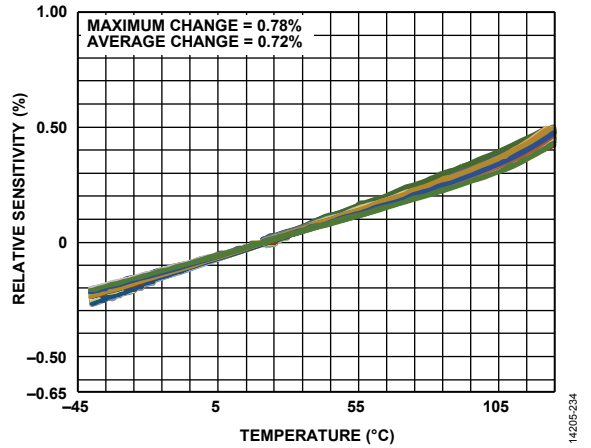


Figure 34. ADXL355 X-Axis Sensitivity Relative to 25°C vs. Temperature

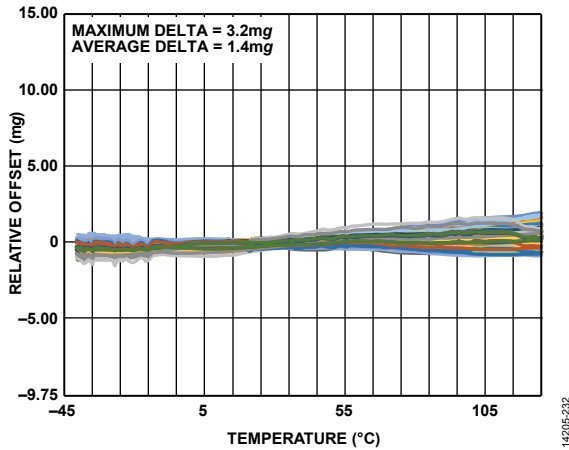


Figure 32. ADXL355 Y-Axis Zero g Offset Relative to 25°C vs. Temperature

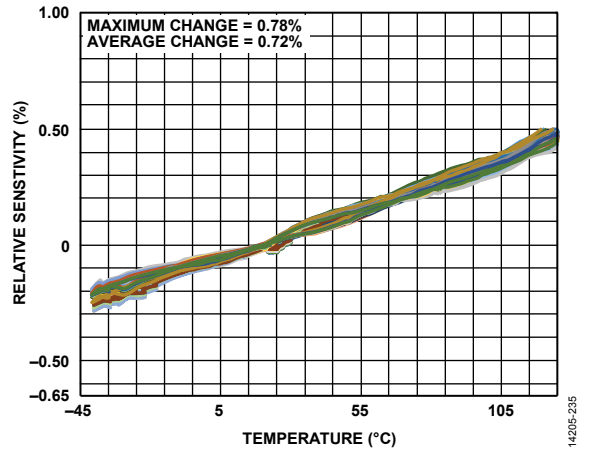


Figure 35. ADXL355 Y-Axis Sensitivity Relative to 25°C vs. Temperature

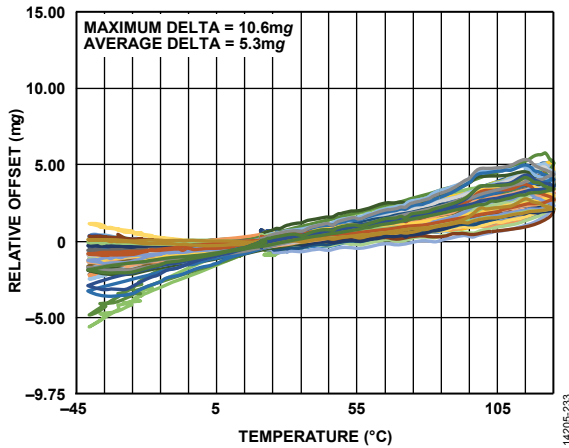


Figure 33. ADXL355 Z-Axis Zero g Offset Relative to 25°C vs. Temperature

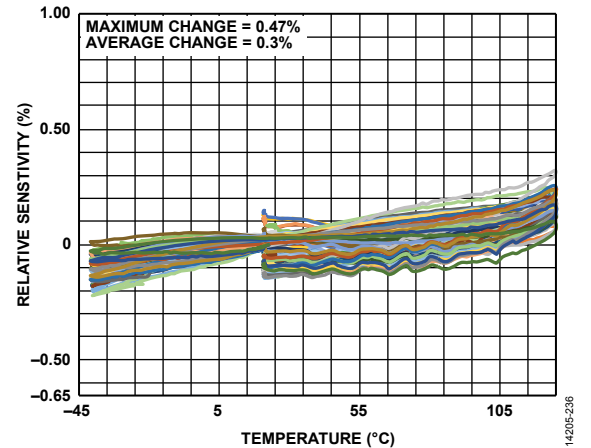


Figure 36. ADXL355 Z-Axis Sensitivity Relative to 25°C vs. Temperature



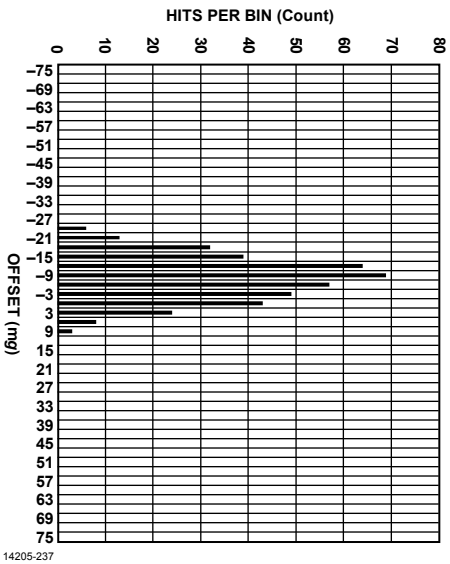


Figure 37. ADXL355 Zero g Offset Histogram at 25°C, X-Axis

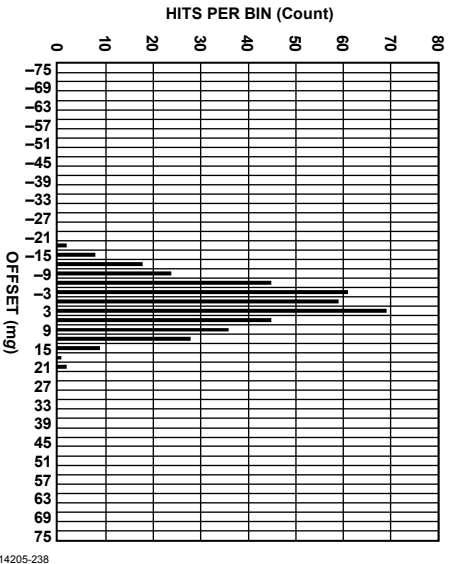


Figure 38. ADXL355 Zero g Offset Histogram at 25°C, Y-Axis

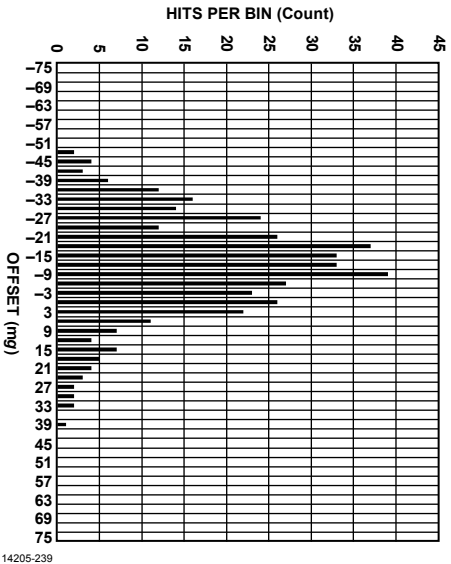


Figure 39. ADXL355 Zero g Offset Histogram at 25°C, Z-Axis

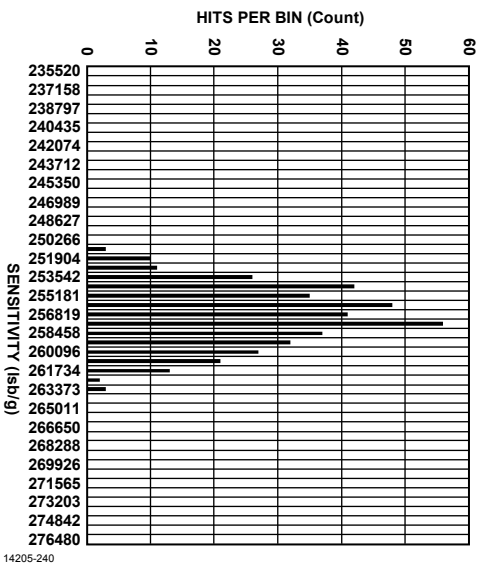


Figure 40. ADXL355 Sensitivity Histogram at 25°C, X-Axis

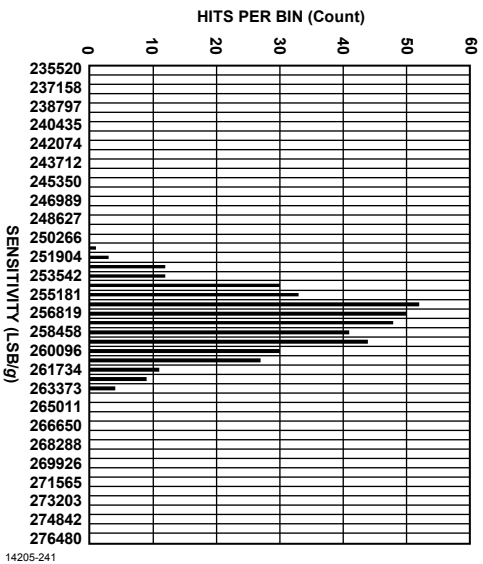


Figure 41. ADXL355 Sensitivity Histogram at 25°C, Y-Axis

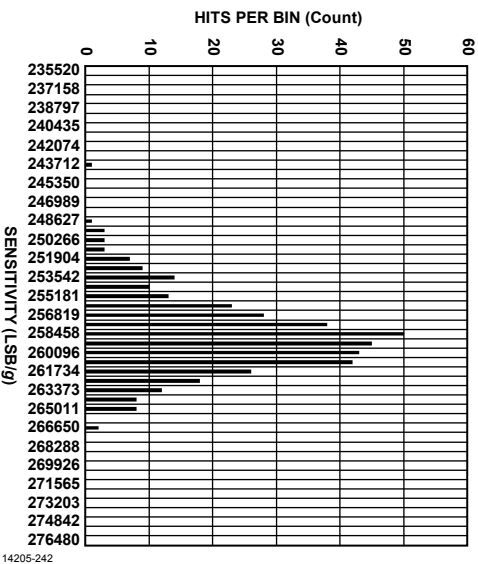


Figure 42. ADXL355 Sensitivity Histogram at 25°C, Z-Axis

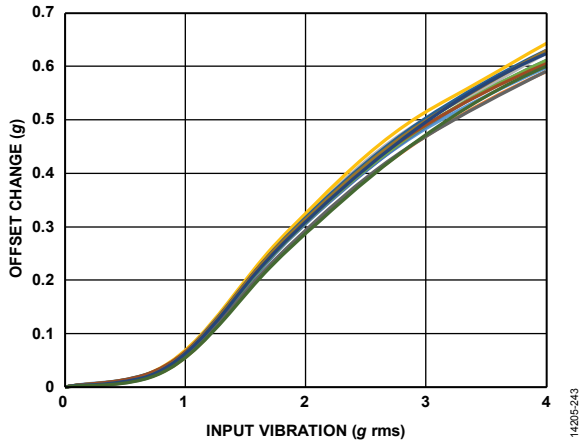


Figure 43. ADXL355 Vibration Rectification Error (VRE), X-Axis Offset from +1 g,  $\pm 2$  g Range, X-Axis Orientation =  $-1$  g

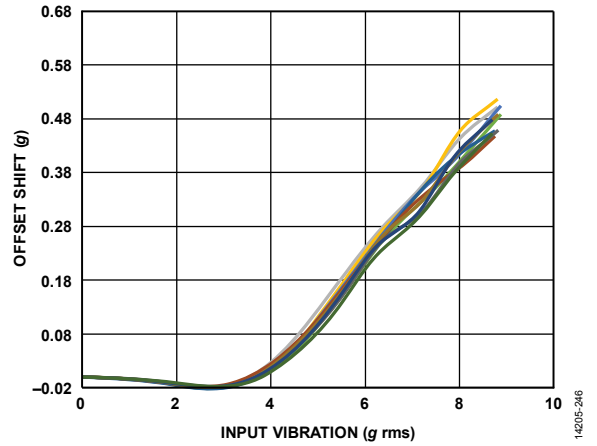


Figure 46. ADXL355 Vibration Rectification Error (VRE), X-Axis Offset from +1 g,  $\pm 8$  g Range, X-Axis Orientation =  $-1$  g

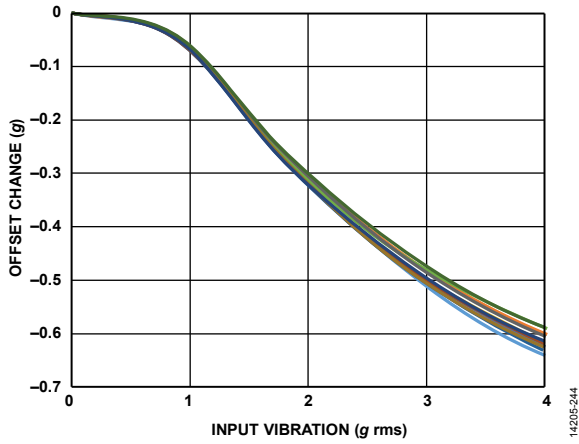


Figure 44. ADXL355 Vibration Rectification Error (VRE), Y-Axis Offset from +1 g,  $\pm 2$  g Range, Y-Axis Orientation =  $+1$  g

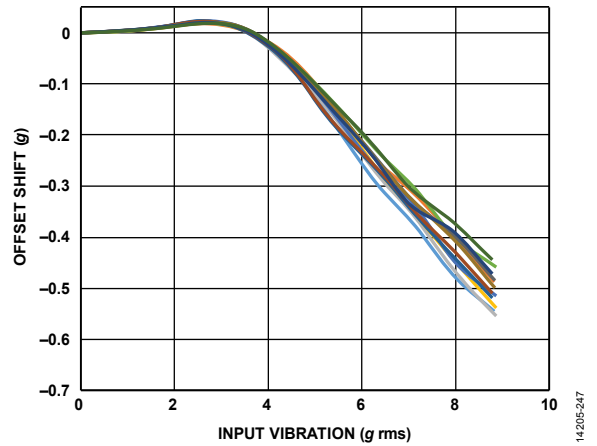


Figure 47. ADXL355 Vibration Rectification Error (VRE), Y-Axis Offset from +1 g,  $\pm 8$  g Range, Y-Axis Orientation =  $+1$  g

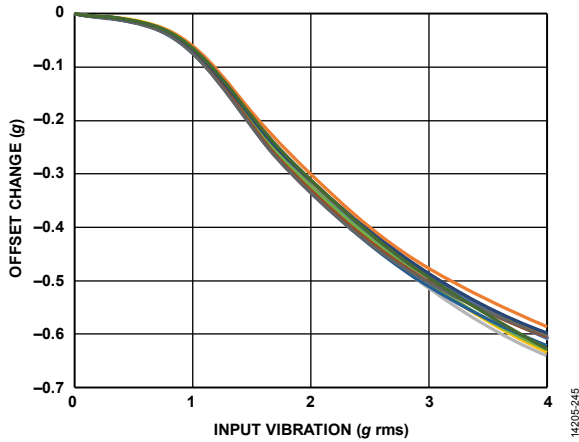


Figure 45. ADXL355 Vibration Rectification Error (VRE), Z-Axis Offset from +1 g,  $\pm 2$  g Range, Z-Axis Orientation =  $+1$  g

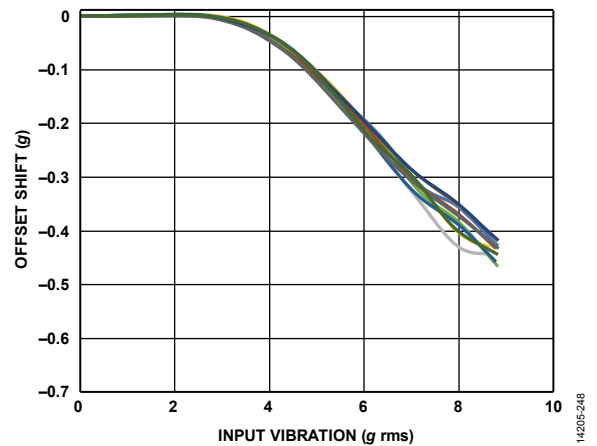


Figure 48. ADXL355 Vibration Rectification Error (VRE), Z-Axis Offset from +1 g,  $\pm 8$  g Range, Z-Axis Orientation =  $+1$  g

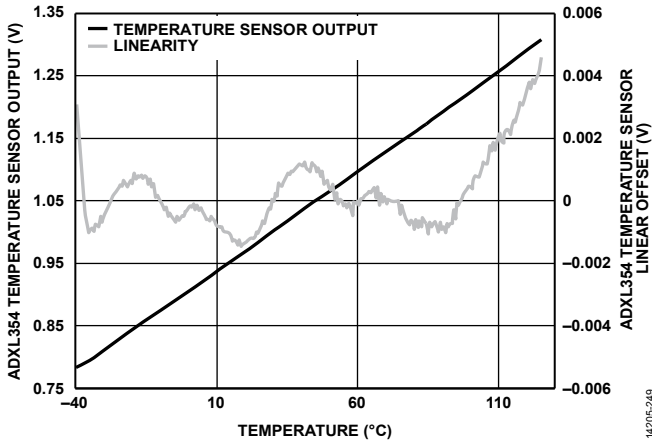


Figure 49. ADXL354 Temperature Sensor Output and Linearity Offset vs. Temperature

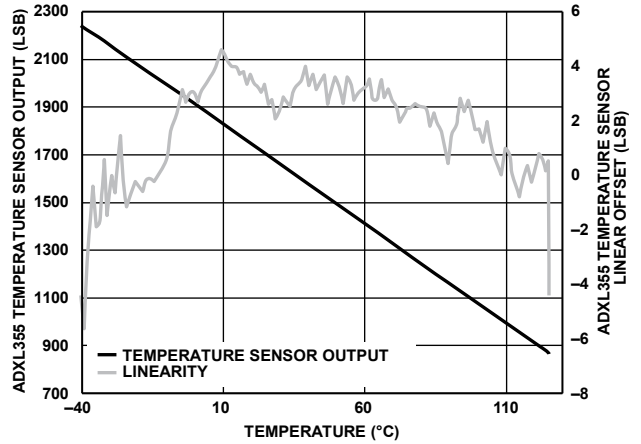


Figure 52. ADXL355 Temperature Sensor Output and Linearity Offset vs. Temperature

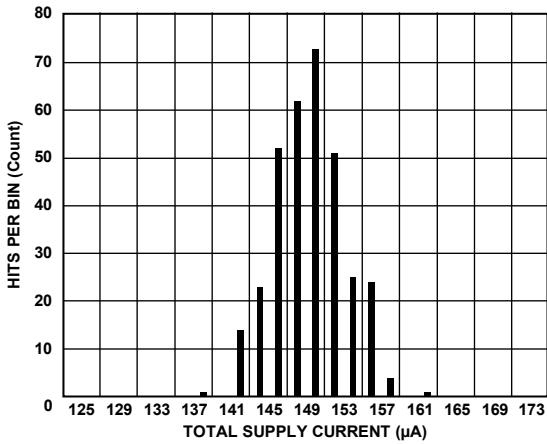


Figure 50. ADXL354 Total Supply Current, 3.3 V

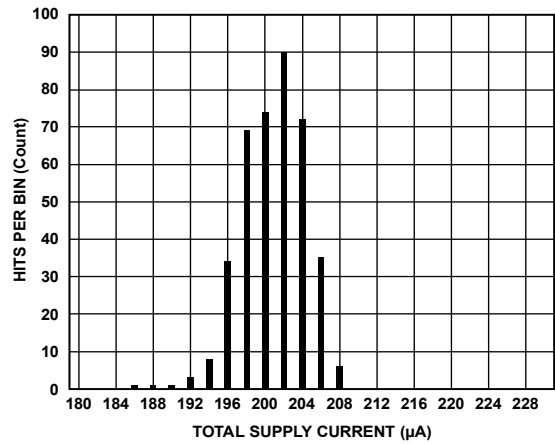


Figure 53. ADXL355 Total Supply Current, 3.3 V

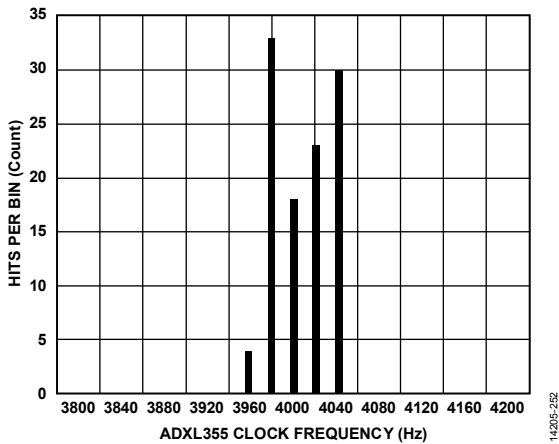


Figure 51. ADXL355 Internal Clock Frequency Histogram

**ROOT ALLAN VARIANCE (RAV) ADXL355 CHARACTERISTICS**

All figures include data for multiple devices and multiple lots, and they were taken in the  $\pm 2$  g range, unless otherwise noted.

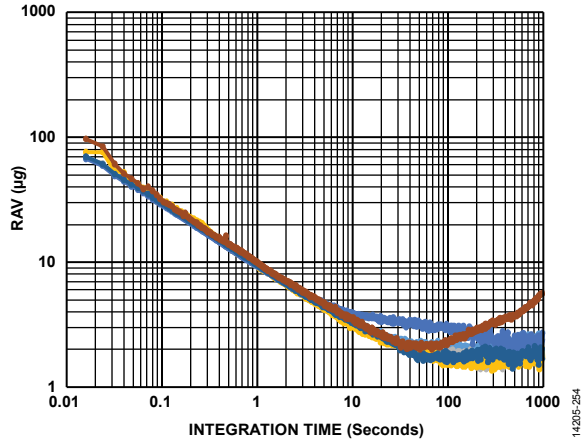


Figure 54. ADXL355 Root Allan Variance (RAV), X-Axis

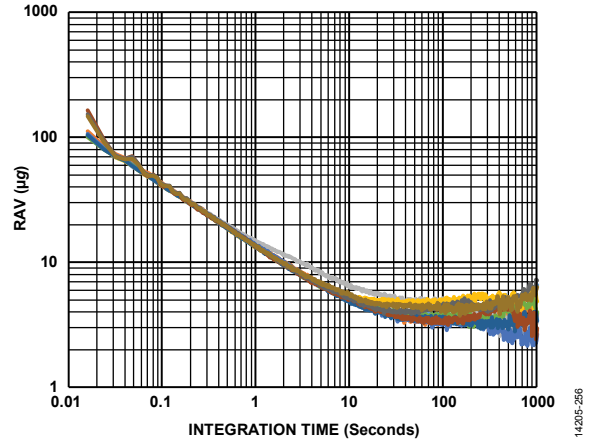


Figure 56. ADXL355 Root Allan Variance (RAV), Z-Axis

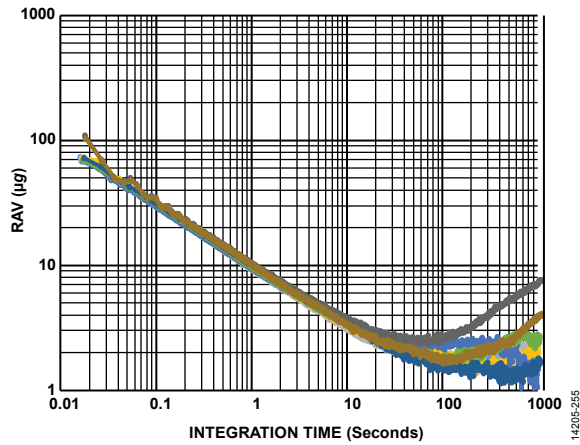


Figure 55. ADXL355 Root Allan Variance (RAV), Y-Axis

## THEORY OF OPERATION

The [ADXL354](#) is a complete 3-axis, ultralow noise and ultrastable offset MEMS accelerometer with outputs ratiometric to the analog 1.8 V supply,  $V_{IP8ANA}$ . The [ADXL355](#) adds three high resolution ADCs that use the analog 1.8 V supply as a reference to provide digital outputs insensitive to the supply voltage. The [ADXL354B](#) is pin selectable for  $\pm 2 g$  or  $\pm 4 g$  full scale, the [ADXL354C](#) is pin selectable for  $\pm 2 g$  or  $\pm 8 g$  full scale, and the [ADXL355](#) is programmable for  $\pm 2.048 g$ ,  $\pm 4.096 g$ , and  $\pm 8.192 g$  full scale. The [ADXL355](#) offers both SPI and I<sup>2</sup>C communications ports.

The micromachined, sensing elements are fully differential, comprising the lateral x-axis and y-axis sensors and the vertical, teeter totter z-axis sensors. The x-axis and y-axis sensors and the z-axis sensors go through separate signal paths that minimize offset drift and noise. The signal path is fully differential, except for a differential to single-ended conversion at the analog outputs of the [ADXL354](#).

The analog accelerometer outputs of the [ADXL354](#) are ratiometric to  $V_{IP8ANA}$ ; therefore, carefully digitize them correctly. The temperature sensor output is not ratiometric. The  $X_{OUT}$ ,  $Y_{OUT}$ , and  $Z_{OUT}$  analog outputs are filtered internally with an anti-aliasing filter. These analog outputs also have an internal 32 k $\Omega$  series resistor that can be used with an external capacitor to set the bandwidth of the output.

The [ADXL355](#) includes antialias filters before and after the high resolution  $\Sigma$ - $\Delta$  ADC. User-selectable output data rates and filter corners are provided. The temperature sensor is digitized with a 12-bit successive approximation register (SAR) ADC.

## ANALOG OUTPUT

Figure 57 shows the [ADXL354](#) application circuit. The analog outputs ( $X_{OUT}$ ,  $Y_{OUT}$ , and  $Z_{OUT}$ ) are ratiometric to the 1.8 V analog voltage from the  $V_{IP8ANA}$  pin.  $V_{IP8ANA}$  can be powered with an on-chip LDO that is powered from  $V_{SUPPLY}$ .  $V_{IP8ANA}$  can also be supplied externally by forcing  $V_{SUPPLY}$  to  $V_{SS}$ , which disables the LDO. Due to the ratiometric response, the analog output requires referencing to the  $V_{IP8ANA}$  supply when digitizing to achieve the inherent noise and offset performance of the [ADXL354](#). The 0 g bias output is nominally equal to  $V_{IP8ANA}/2$ . The recommended option is to use the [ADXL354](#) with a ratiometric ADC (for example, the Analog Devices, Inc., [AD7682](#)) with  $V_{IP8ANA}$  providing the voltage reference. This configuration results in self cancellation of errors due to minor supply variations.

The [ADXL354](#) outputs two forms of filtering: internal anti-aliasing filtering with a cutoff frequency of approximately 1.5 kHz, and external filtering. The external filter uses a fixed, on-chip, 32 k $\Omega$  resistance in series with each output in conjunction with the external capacitors to implement the low-pass filter antialiasing and noise reduction prior to the external ADC. The antialias filter cutoff frequency must be significantly higher than the desired signal bandwidth. If the antialias filter corner is too low, ratiometricity can be degraded where the signal attenuation is different than the reference attenuation.

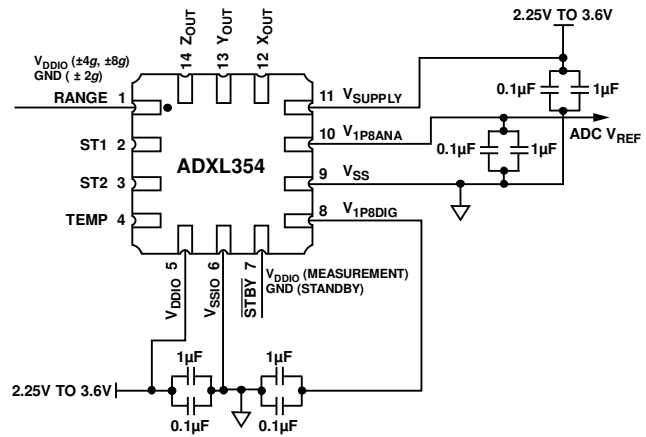


Figure 57. [ADXL354](#) Application Circuit

14-005-022

**DIGITAL OUTPUT**

Figure 59 shows the ADXL355 application circuit with the recommended bypass capacitors. The communications interface is either SPI or I<sup>2</sup>C (see the Serial Communications section for additional information).

The ADXL355 includes an internal configurable digital band-pass filter. Both the high-pass and low-pass poles of the filter are adjustable, as detailed in the Filter Settings Register section and Table 43. At power-up, the default conditions for the filters are as follows:

- High-pass filter (HPF) = dc (off)
- Low-pass filter (LPF) = 1000 Hz
- Output data rate = 4000 Hz

**AXES OF ACCELERATION SENSITIVITY**

Figure 58 shows the axes of acceleration sensitivity. Note that the output voltage increases when accelerated along the sensitive axis.

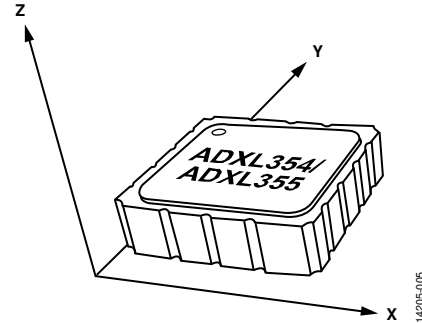


Figure 58. Axes of Acceleration Sensitivity

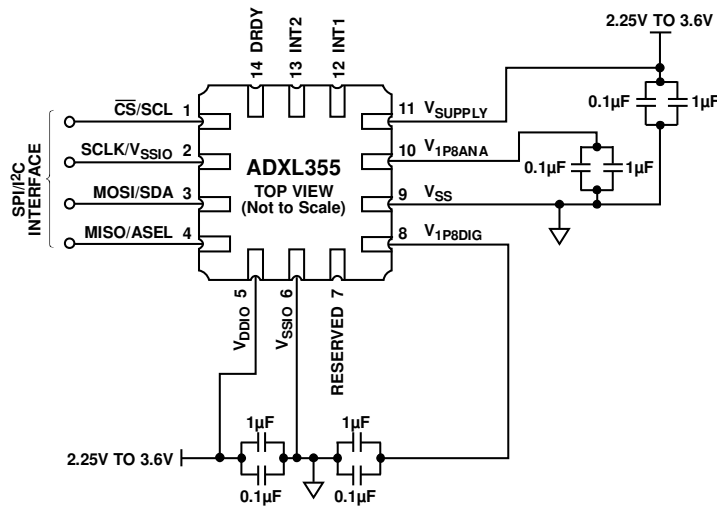


Figure 59. ADXL355 Application Circuit

## POWER SEQUENCING

There are two methods for applying power to the device. Typically, internal LDO regulators generate the 1.8 V power for the analog and digital supplies,  $V_{IP8ANA}$  and  $V_{IP8DIG}$ , respectively. Optionally, connecting  $V_{SUPPLY}$  to  $V_{SS}$  and driving  $V_{IP8ANA}$  and  $V_{IP8DIG}$  with an external supply can supply  $V_{IP8ANA}$  and  $V_{IP8DIG}$ .

When using the internal LDO regulators, connect  $V_{SUPPLY}$  to a voltage source between 2.25 V to 3.6 V. In this case,  $V_{DDIO}$  and  $V_{SUPPLY}$  can be powered in parallel.  $V_{SUPPLY}$  must not exceed the  $V_{DDIO}$  voltage by greater than 0.5 V. If necessary,  $V_{DDIO}$  can be powered before  $V_{SUPPLY}$ .

When disabling the internal LDO regulators and using an external 1.8 V supply to power  $V_{IP8ANA}$  and  $V_{IP8DIG}$ , tie  $V_{SUPPLY}$  to ground, and set  $V_{IP8ANA}$  and  $V_{IP8DIG}$  to the same final voltage level. In the case of bypassing the LDOs, the recommended power sequence is to apply power to  $V_{DDIO}$ , followed by applying power to  $V_{IP8DIG}$  approximately 10  $\mu$ s later, and then applying power to  $V_{IP8ANA}$  approximately 10  $\mu$ s later. If necessary,  $V_{IP8DIG}$  and  $V_{DDIO}$  can be powered from the same 1.8 V supply, which can also be tied to  $V_{IP8ANA}$  with proper isolation. In this case, proper decoupling and low frequency isolation is important to maintain the noise performance of the sensor.

## POWER SUPPLY DESCRIPTION

The [ADXL354/ADXL355](#) have four different power supply domains:  $V_{SUPPLY}$ ,  $V_{IP8ANA}$ ,  $V_{IP8DIG}$ , and  $V_{DDIO}$ . The internal analog and digital circuitry operates at 1.8 V nominal.

### $V_{SUPPLY}$

$V_{SUPPLY}$  is 2.25 V to 3.6 V, which is the input range to the two LDO regulators that generate the nominal 1.8 V outputs for  $V_{IP8ANA}$  and  $V_{IP8DIG}$ . Connect  $V_{SUPPLY}$  to  $V_{SS}$  to disable the LDO regulators, which allows driving  $V_{IP8ANA}$  and  $V_{IP8DIG}$  from an external source.

### $V_{IP8ANA}$

All sensor and analog signal processing circuitry operates in this domain. Offset and sensitivity of the analog output [ADXL354](#) are ratiometric to this supply voltage. When using external ADCs, use  $V_{IP8ANA}$  as the reference voltage. The digital output [ADXL355](#) includes ADCs that are ratiometric to  $V_{IP8ANA}$ , thereby rendering offset and sensitivity insensitive to the value of  $V_{IP8ANA}$ .  $V_{IP8ANA}$  can be an input or an output as defined by the state of the  $V_{SUPPLY}$  voltage.

### $V_{IP8DIG}$

$V_{IP8DIG}$  is the supply voltage for the internal logic circuitry. A separate LDO regulator decouples the digital supply noise from the analog signal path.  $V_{IP8ANA}$  can be an input or an output as defined by the state of the  $V_{SUPPLY}$  voltage. If driven externally,  $V_{IP8DIG}$  must be the same voltage as the  $V_{IP8ANA}$  voltage.

### $V_{DDIO}$

The  $V_{DDIO}$  value determines the logic high levels. On the analog output [ADXL354](#),  $V_{DDIO}$  sets the logic high level for the self test pins, ST1 and ST2, as well as the STBY pin. On the digital output [ADXL355](#),  $V_{DDIO}$  sets the logic high level for communications interface ports, as well as the interrupt and DRDY outputs.

The LDO regulators are operational when  $V_{SUPPLY}$  is between 2.25 V and 3.6 V.  $V_{IP8ANA}$  and  $V_{IP8DIG}$  are the regulator outputs in this mode. Alternatively, when tying  $V_{SUPPLY}$  to  $V_{SS}$ ,  $V_{IP8ANA}$  and  $V_{IP8DIG}$  are supply voltage inputs with a 1.62 V to 1.98 V range.

## OVERRANGE PROTECTION

To avoid electrostatic capture of the proof mass when the accelerometer is subject to input acceleration beyond its full-scale range, all sensor drive clocks turn off for 0.5 ms. In the  $\pm 2\text{ g}/\pm 2.048\text{ g}$  range setting, the overrange protection activates for input signals beyond approximately  $\pm 8\text{ g}/\pm 8.192\text{ g}$  ( $\pm 25\%$ ), and for the  $\pm 4\text{ g}/\pm 4.096\text{ g}$  and  $\pm 8\text{ g}/\pm 8.192\text{ g}$  range setting, the threshold corresponds to about  $\pm 16\text{ g}$  ( $\pm 25\%$ ).

When overrange protection occurs, the  $X_{OUT}$ ,  $Y_{OUT}$ , and  $Z_{OUT}$  pins on the [ADXL354](#) begin to drive to midscale. The [ADXL355](#) floats toward zero, and first in, first out (FIFO) begins filling with this data.

## SELF TEST

The [ADXL354](#) and [ADXL355](#) incorporate a self test feature that effectively tests their mechanical and electronic systems simultaneously. In [ADXL354](#), drive the ST1 pin to  $V_{DDIO}$  to invoke self test mode. Then, by driving the ST2 pin to  $V_{DDIO}$ , the [ADXL354](#) applies an electrostatic force to the mechanical sensor and induces a change in output in response to the force. The self test delta (or response) is the difference in output voltages between when ST2 is high and ST2 is low, both when ST1 is asserted. After the self test measurement is complete, bring both pins low to resume normal operation.

The self test operation is similar in the [ADXL355](#), except ST1 and ST2 can be accessed through the SELF\_TEST register (Register 0x2E).

The self test feature rejects externally applied acceleration and only responds to the self test force, which allows an accurate measurement of the self test, even in the presence of external mechanical noise.

**FILTER**

The ADXL354/ADXL355 use an analog, low-pass, antialiasing filter to reduce out of band noise and to limit bandwidth. The ADXL355 provides further digital filtering options to maintain excellent noise performance at various ODRs.

The analog, low-pass antialiasing filter in the ADXL354/ADXL355 provides a fixed bandwidth of approximately 1.5 kHz, which is where the output response is attenuated by approximately 50%. The shape of the filter response in the frequency domain is that of a sinc3 filter.

The ADXL354 x-axis, y-axis, and z-axis analog outputs include an amplifier followed by a series 32 kΩ resistor and output to the X<sub>OUT</sub>, the Y<sub>OUT</sub>, and the Z<sub>OUT</sub> pins, respectively.

The ADXL355 provides an internal 20-bit, Σ-Δ ADC to digitize the filtered analog signal. Additional digital filtering (beyond the analog, low-pass, antialiasing filter) consists of a low-pass digital decimation filter and a bypassable high-pass filter that supports output data rates between 4 kHz and 3.9 Hz. The decimation filter consists of two stages. The first stage is fixed decimation with a 4 kHz ODR with a low-pass filter cutoff (50% reduction in output response) at about 1 kHz. A variable second stage decimation filter is used for the 2 kHz output data rate and below (it is bypassed for 4 kHz ODR). Figure 60 shows the low-pass filter response with a 1 kHz corner (4 kHz ODR) for the

ADXL355. Note that Figure 60 does not include the fixed frequency analog, low-pass, antialiasing filter with a fixed bandwidth of approximately 1.5 kHz.

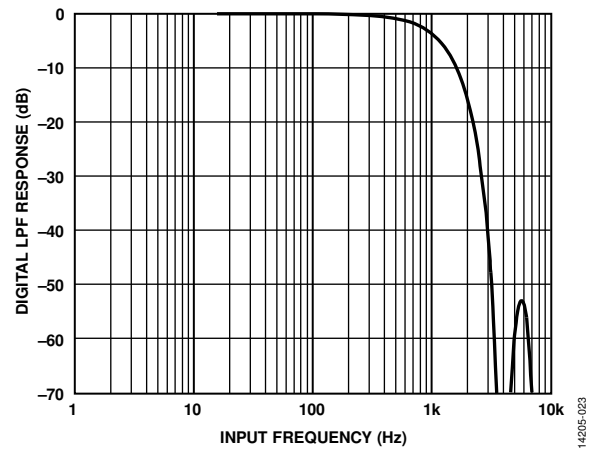


Figure 60. ADXL355 Digital Low-Pass Filter (LPF) Response for 4 kHz ODR

The ADXL355 pass band of the signal path relates to the combined filter responses, including the analog filter previously discussed, and the digital decimation filter/ODR setting. Table 9 shows the delay associated with the decimation filter for each setting and provides the attenuation at the ODR/4 corner.

**Table 9. Digital Filter Group Delay and Profile**

Programmed ODR (Hz)	Delay		Attenuation	
	ODR (Cycles)	Time (ms)	Decimator at ODR/4 (dB)	Full Path at ODR/4 (dB)
4000	2.52	0.63	-3.44	-3.63
4000/2 = 2000	2.00	1.00	-2.21	-2.26
4000/4 = 1000	1.78	1.78	-1.92	-1.93
4000/8 = 500	1.63	3.26	-1.83	-1.83
4000/16 = 250	1.57	6.27	-1.83	-1.83
4000/32 = 125	1.54	12.34	-1.83	-1.83
4000/64 = 62.5	1.51	24.18	-1.83	-1.83
4000/128 ~ 31	1.49	47.59	-1.83	-1.83
4000/256 ~ 16	1.50	96.25	-1.83	-1.83
4000/512 ~ 8	1.50	189.58	-1.83	-1.83
4000/1024 ~ 4	1.50	384.31	-1.83	-1.83



The ADXL355 also includes an optional digital high-pass filter with a programmable corner frequency. By default, the high-pass filter is disabled. The high pass corner frequency, where the output is attenuated by 50%, is related to the ODR, and the HPF\_CORNER setting in the filter register (Register 0x28, Bits[6:4]). Table 10 shows the HPF\_CORNER response. Figure 61 and Figure 62 show the simulated high-pass filter response and delay for a 10 Hz cutoff.

The ADXL355 also includes an interpolation filter after the decimation filters to produce oversampled/upconverted data that provides an external synchronization option. See the Data Synchronization section for more details. Table 11 shows the delay and attenuation relative to the programmed ODR.

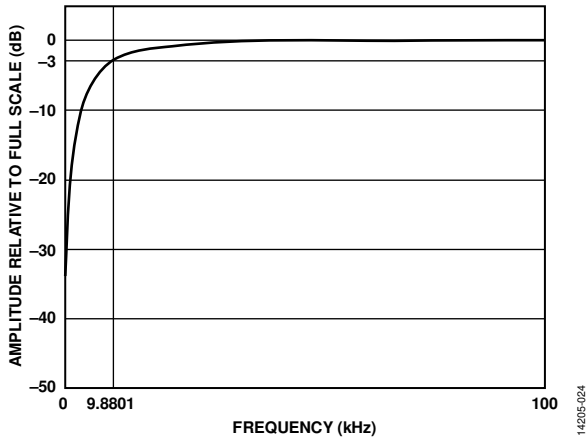


Figure 61. High-Pass Filter Pass-Band Response for a 4 kHz ODR and an HPF\_CORNER Setting of 001 (Register 0x28, Bits[6:4])

Group delay is the digital filter delay from the input to the ADC until data is available at the interface (see the Filter section). This delay is the largest component of the total delay from sensor to serial interface.

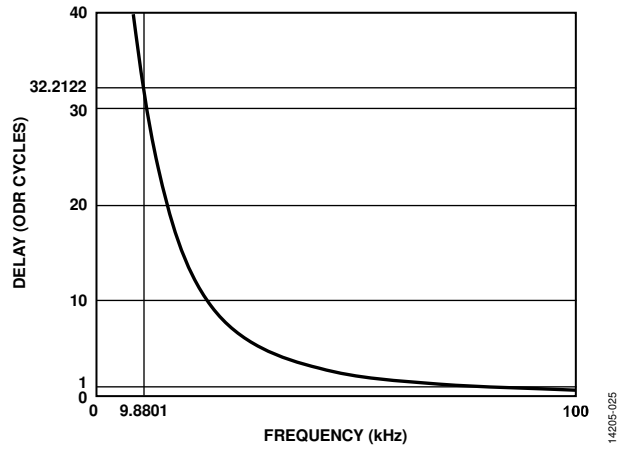


Figure 62. High-Pass Filter Delay Response for a 4 kHz ODR and an HPF\_CORNER Setting of 001 (Register 0x28, Bits[6:4])

**Table 10. Digital High-Pass Filter Response**

HPF_CORNER Register Setting (Register 0x28, Bits[6:4])	HPF_CORNER Frequency, -3 dB Point Relative to ODR Setting	-3 dB at 4 kHz ODR (Hz)
000	Not applicable, no high-pass filter enabled	Off
001	$24.7 \times 10^{-4} \times \text{ODR}$	9.88
010	$6.2084 \times 10^{-4} \times \text{ODR}$	2.48
011	$1.5545 \times 10^{-4} \times \text{ODR}$	0.62
100	$0.3862 \times 10^{-4} \times \text{ODR}$	0.1545
101	$0.0954 \times 10^{-4} \times \text{ODR}$	0.03816
110	$0.0238 \times 10^{-4} \times \text{ODR}$	0.00952

**Table 11. Combined Digital Interpolation Filter and Decimation Filter Response**

Interpolator Data Rate Resolution Relative to $64 \times \text{ODR}$ (Hz)	Combined Interpolator/Decimator Delay (ODR Cycles)	Combined Interpolator/Decimator Delay (ms)	Combined Interpolator/Decimator Output Attenuation at ODR/4 (dB)
$64 \times 4000 = 256000$	3.51661	0.88	-6.18
$64 \times 2000 = 128000$	3.0126	1.51	-4.93
$64 \times 1000 = 64000$	2.752	2.75	-4.66
$64 \times 500 = 32000$	2.6346	5.27	-4.58
$64 \times 250 = 16000$	2.5773	10.31	-4.55
$64 \times 125 = 8000$	2.5473	20.38	-4.55
$64 \times 62.5 = 4000$	2.53257	40.52	-4.55
$64 \times 31.25 = 2000$	2.52452	80.78	-4.55
$64 \times 15.625 = 1000$	2.52045	161.31	-4.55
$64 \times 7.8125 = 500$	2.5194	322.48	-4.55
$64 \times 3.90625 = 250$	2.51714	644.39	-4.55

## SERIAL COMMUNICATIONS

The 4-wire serial interface communicates in either the SPI or I<sup>2</sup>C protocol. It affectively autodetects the format being used, requiring no configuration control to select the format.

### SPI PROTOCOL

Wire the [ADXL355](#) for SPI communication as shown in the connection diagram in Figure 63. The SPI protocol timing is shown in Figure 64 to Figure 67. The timing scheme follows the clock polarity (CPOL) = 0 and clock phase (CPHA) = 0. The SPI clock speed ranges from 100 kHz to 10 MHz.

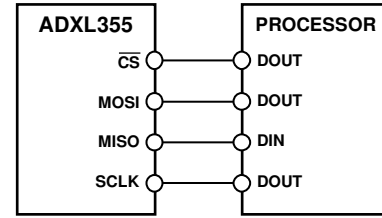


Figure 63. 4-Wire SPI Connection

14205-026

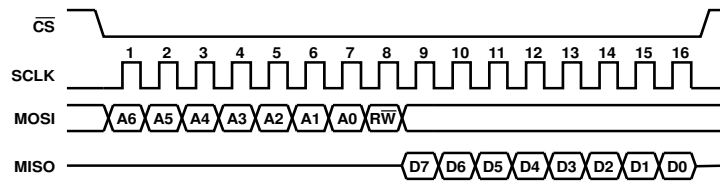


Figure 64. SPI Timing Diagram—Single-Byte Read

14205-027

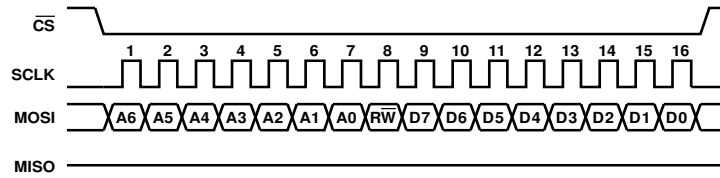


Figure 65. SPI Timing Diagram—Single-Byte Write

14205-028

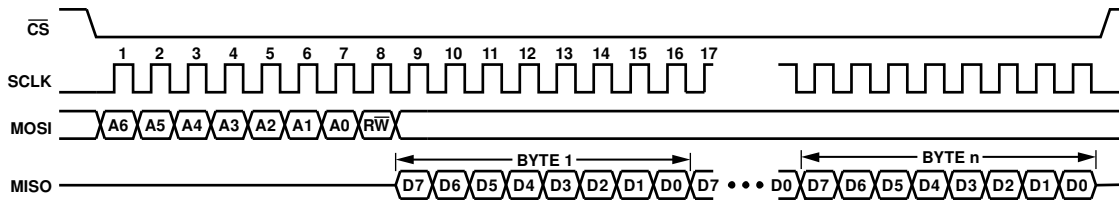


Figure 66. SPI Timing Diagram—Multibyte Read

14205-029

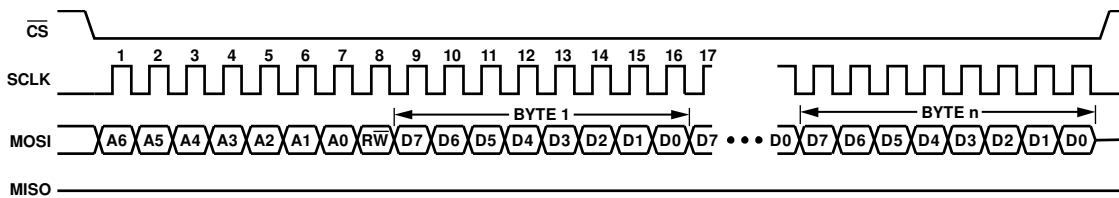


Figure 67. SPI Timing Diagram—Multibyte Write

14205-030